

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10659593	LEE, BAEK-WOON
	<b>Examiner</b> Sherman, Stephen G	<b>Art Unit</b> 2629

<b>SEARCHED</b>			
-----------------	--	--	--

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
345	88,600,603-605,613,87-102	11/29/2006	SS
349	56,82,84,109,143	11/29/2006	SS
349	139	4/16/2007	SS

<b>SEARCH NOTES</b>			
<b>Search Notes</b>		<b>Date</b>	<b>Examiner</b>
See attached search history			
Search Updated		11/29/2006	SS
Search Updated		4/16/2007	SS
Search Updated		8/22/2007	SS

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>